L Number	Hits	Search Text	DB	Time stamp
3	166485	compar\$4 with (data profile static\$4)	USPAT	2004/11/29 18:41
4	126167	(identif\$5 determin\$5 detect\$4) with (fail\$4 defect\$4 fault\$4	USPAT	2004/11/29 18:42
-	,,,	malfunction\$4)		
5	417	thin adj film adj transistor with (fail\$4 defect\$4 fault\$4	USPAT	2004/11/29 18:42
		malfunction\$4)		
6	24538	(compar\$4 with (data profile static\$4)) and ((identif\$5	USPAT	2004/11/29 18:42
		determin\$5 detect\$4) with (fail\$4 defect\$4 fault\$4		
[malfunction\$4))	1	
7	16	(thin adj film adj transistor with (fail\$4 defect\$4 fault\$4	USPAT	2004/11/29 19:08
		malfunction\$4)) and ((compar\$4 with (data profile static\$4))		
-		and ((identif\$5 determin\$5 detect\$4) with (fail\$4 defect\$4		
	0	fault\$4 malfunction\$4))) look adj up adj table with (relat\$4 correspon\$4 associtat\$4)	USPAT	2004/11/29 19:10
8	U	with (manufactur\$4 fabricat\$4 making) with (fail\$4	USPAI	2004/11/29 19.10
		malfunction\$4 fault\$4 defect\$4) with compar\$4		
9	0	look adj up adj table same (relat\$4 correspon\$4 associtat\$4)	USPAT	2004/11/29 19:11
		same (manufactur\$4 fabricat\$4 making) same (fail\$4	00.7	200 11 11/20 10:11
		malfunction\$4 fault\$4 defect\$4) same compar\$4		
10	1483	look adj up adj table and (relat\$4 correspon\$4 associtat\$4)	USPAT	2004/11/29 19:11
		and (manufactur\$4 fabricat\$4 making) and (fail\$4		
		malfunction\$4 fault\$4 defect\$4) same compar\$4		
12	0	(thin adj film adj transistor with (fail\$4 defect\$4 fault\$4	USPAT	2004/11/29 19:12
		malfunction\$4)) and (look adj up adj table same (relat\$4		'
		correspon\$4 associtat\$4) same (manufactur\$4 fabricat\$4		
		making) and (fail\$4 malfunction\$4 fault\$4 defect\$4) with		
	00	compar\$4)	LICDAT	0004/44/00 40:00
11	22	look adj up adj table same (relat\$4 correspon\$4 associtat\$4) same (manufactur\$4 fabricat\$4 making) and (fail\$4	USPAT	2004/11/29 19:20
1		malfunction\$4 fault\$4 defect\$4) with compar\$4		
13	271	(predefined predetermined) adj3 (defect\$4 fail\$4 fault\$4	USPAT	2004/11/29 19:22
'	271	malfunction\$4) with (profile table classification stored)	001 711	200 17 1720 10:22
14	2	(thin adj film adj transistor with (fail\$4 defect\$4 fault\$4	USPAT	2004/11/29 19:22
		malfunction\$4)) and ((predefined predetermined) adj3		
		(defect\$4 fail\$4 fault\$4 malfunction\$4) with (profile table		
		classification stored))		1
-	14	(thin adj film adj transistor with (manufactur\$4 fabricat\$4	USPAT	2004/11/29 18:41
		making)) same ((identif\$5 determin\$5 detect\$4) with (fail\$4		
	_	defect\$4 fault\$4 malfunction\$4))	LICDAT	0004/44/00 44:40
-	7	((thin adj film adj transistor with (manufactur\$4 fabricat\$4	USPAT	2004/11/29 14:48
		making)) same ((identif\$5 determin\$5 detect\$4) with (fail\$4		
		defect\$4 fault\$4 malfunction\$4))) and ((apply\$4 applies inject\$4) and (compar\$4 identif\$4 determin\$4))		
_	1	15546013.pn.	USPAT	2004/11/29 14:48
_	401	(identif\$5 determin\$5 detect\$4) with caus\$4 adj3 (fail\$4	USPAT	2004/11/29 16:11
		defect\$4 fault\$4 malfunction\$4) with (manufactur\$4 making	1	
		fabricat\$4)		
- 	3432	thin adj film adj transistor with (manufactur\$4 fabricat\$4	USPAT	2004/11/29 16:12
		making)		
-	7	((identif\$5 determin\$5 detect\$4) with caus\$4 adj3 (fail\$4	USPAT	2004/11/29 16:12
		defect\$4 fault\$4 malfunction\$4) with (manufactur\$4 making		
		fabricat\$4)) and (thin adj film adj transistor with		
	1042044	(manufactur\$4 fabricat\$4 making))	LICDAT	2004/11/20 46:40
-	1043811	(apply\$4 applies inject\$4) and (compar\$4 identif\$4	USPAT	2004/11/29 16:16
		determin\$4)	1	